



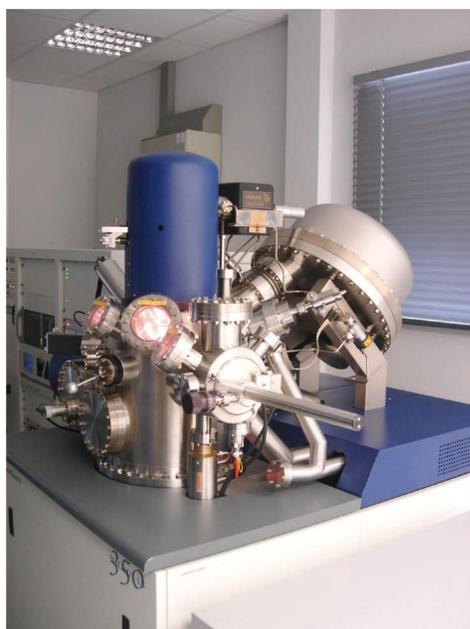
European PhD School on

## “NANOANALYSIS USING FINELY FOCUSED ION AND ELECTRON BEAMS”

BELVAUX, Luxembourg  
March 13<sup>th</sup> – 17<sup>th</sup> 2006

“SECONDARY ION MASS SPECTROMETRY (SIMS),  
TRANSMISSION ELECTRON MICROSCOPY (TEM),  
AUGER ELECTRON SPECTROSCOPY (AES):  
A COMPREHENSIVE OVERVIEW”

- > Ion and electron - matter interactions
- > Instrumentation
- > Applications



The PhD School organized by the NANOBEAMS NoE focuses on SIMS, TEM and AES.  
It consists of four different weeks composing a two year cycle:

- > The first week provides an overview of the three techniques
- > The three other weeks aim at forming specialists in the field

Each week proposes theoretical tutorials and practical sessions.

### REGISTRATION

No registration fees

Application deadline: 27<sup>th</sup> February 2006

Audience: scientists with a degree in physics, biology and material science  
30 attendees maximum

Teaching program and Application: [www.nanobeams.org](http://www.nanobeams.org)

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